

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12406-017001	Application No. 09/830,038
<b>Information Disclosure Statement</b> <b>by Applicant</b> (Use several sheets if necessary)		Applicant Hohn et al.	
		Filing Date April 20, 2003	Group Art Unit 2827

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
TD	AA	5,973,337	10/26/1999	Knapp et al.	—	—	—
TD	AB	6,381,838 B1	05/07/02	Ahn et al.	—	—	—
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
TD	AQ	English Abstract of TW 413873.
TD	AR	Examination Report dated December 26, 2001 for TW Application No. 89119316.
	AS	
	AT	

Examiner Signature <i>Tuan B. W.</i>	Date Considered 9-10-04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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(37 CFR §1.98(b))

Applicant  
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April 20, 2003Group Art Unit  
2827**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>JD</i>	AA	5,370,971	12/06/1994	Ogawa et al.	—	—	—
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>JD</i>	AL	JP 6106874	04/19/1994	Japan	<i>F</i>	<i>I</i>	X	—
<i>JD</i>	AM	JP 54135845	10/22/1979	Japan	<i>F</i>	<i>I</i>	X	—
<i>JD</i>	AN	JP 5127378	05/25/1993	Japan	<i>F</i>	<i>I</i>	—	—
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

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	AR	
	AS	
	AT	

Examiner Signature

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*1-10-04*

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